ETS’09 Tutorials

Monday, May 25

9:00 – 13:00

TTEP Tutorial 1
Advanced Topics and Recent Advances in Silicon Debug and Diagnosis

14:30 – 17:30

TTEP Tutorial 1
Advanced Topics and Recent Advances in Silicon Debug and Diagnosis

20:00 – 22:00

Welcome Reception
Session 8A
Advanced Testing
Mem., Power Trans., Microfluidic Syst.

Session 8B
Recent Advances in ATPG

Session 8C
Student’s Forum

Session 9 - Coffee Break and STUDENT’S POSTERS

Session 10A
Advanced External Test of Mixed-Signal Cores

Session 10B
Diagnosis and Dependability Analysis

Session 10C
Special
Soft Errors in Electronic Systems

Session 11A
Emb. Tutorial 1
Switching Noise and Process Var. Challenges in Delay Testing

Session 11B
Emb. Tutorial 2
Test Challenges and Solutions in TSV-Based 3D Stacked ICs

Social Program
<table>
<thead>
<tr>
<th>Time</th>
<th>Session 12A</th>
<th>Session 12B</th>
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<tr>
<td>9:00 – 10:30</td>
<td>Impact of Nanometer Technol. in the Testing Methodology</td>
<td>DfT and Embedded Test</td>
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<td>10:30 – 11:30</td>
<td><strong>Session 13 - POSTER III</strong> and Coffee Break</td>
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<td>11:30 – 12:30</td>
<td><strong>Session 14A</strong></td>
<td><strong>Session 14B</strong></td>
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<td>Emb. Tutorial 3</td>
<td>Emb. Tutorial 4</td>
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<td>Ensuring High Testability without Degrading Security</td>
<td>On-chip Delay Measurement Tech. for Production Test – from D to A</td>
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<td>12:30 – 13:00</td>
<td><strong>Session 15 - Plenary Closing</strong></td>
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**lunch**
ETS’09 Fringe Workshop

Friday, May 29

9:00 – 13:00
Lp on TR
Impact of Low-Power design on Test and Reliability

14:30 – 17:00
LP on TR
Impact of Low-Power design on Test and Reliability

lunch